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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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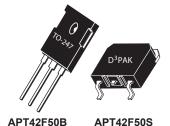


APT42F50B APT42F50S

500V, 42A, 0.13Ω Max, t_{rr}, ≤260ns

N-Channel FREDFET

Power MOS 8^{TM} is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of $C_{\text{rss}}/C_{\text{iss}}$ result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



Single die FREDFET



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- · ZVS phase shifted and other full bridge
- · Half bridge
- · PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I_	Continuous Drain Current @ T _C = 25°C	42	
'D	Continuous Drain Current @ T _C = 100°C	27	А
I _{DM}	Pulsed Drain Current ^①	135	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy ©	930	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	21	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P _D	Total Power Dissipation @ T _C = 25°C			625	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.20	°C/W	
R _{ecs}	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11			
T _J ,T _{STG}	Operating and Storage Junction Temperature Range	-55		150	- °C	
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight		0.22		OZ	
			6.2		g	
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in·lbf	
				1.1	N·m	

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250\mu A$		500			V
$\Delta V_{BR(DSS)} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250µA			0.60		V/°C
R _{DS(on)}	Drain-Source On Resistance [®]	V _{GS} = 10V, I _D = 21A			0.11	0.13	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 1 \text{mA}$		2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-10		mV/°C
,	Zero Gate Voltage Drain Current	V _{DS} = 500V	T _J = 25°C			250	μA
DSS		V _{GS} = 0V	T _J = 125°C	·	·	1000] [
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V		·	·	±100	nA

Dynamic Characteristics

T₁ = 25°C unless otherwise specified

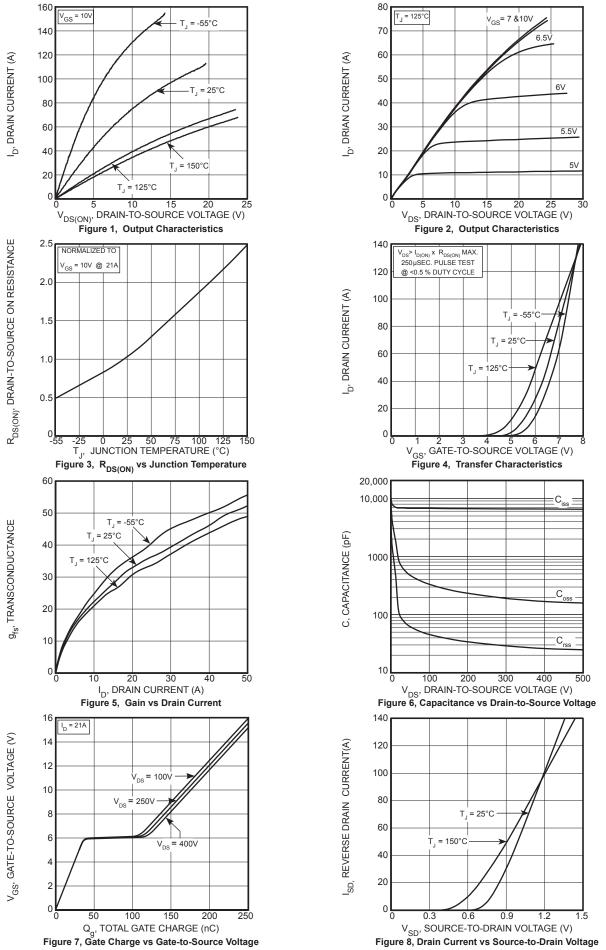
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
g _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 21A		32		S
C _{iss}	Input Capacitance	V 0V V 05V		6810		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		90		
C _{oss}	Output Capacitance			735		
$C^{o(cr)} {}^{\textstyle \textcircled{d}}$	Effective Output Capacitance, Charge Related	V = 0V V = 0V to 222V		425		pF
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 333V$		215		
Q_g	Total Gate Charge	V 01.40V 1.04A		170		
Q _{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 21A,$		38		nC
Q _{gd}	Gate-Drain Charge	V _{DS} = 250V		80		
t _{d(on)}	Turn-On Delay Time	Resistive Switching		29		
t _r	Current Rise Time	V _{DD} = 333V, I _D = 21A		35		ns
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 4.7\Omega^{\textcircled{6}}, V_{GG} = 15V$		80		115
t _f	Current Fall Time	1		26		

Source-Drain Diode Characteristics

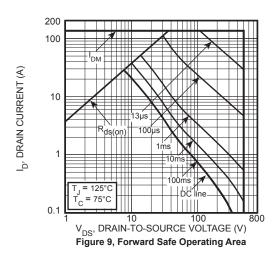
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
I _s	Continuous Source Current (Body Diode)	showing the	D		42	A
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)	s		135	Α
V _{SD}	Diode Forward Voltage	I _{SD} = 21A, T _J = 25°C, V _{GS} = 0V			1.2	V
t _{rr}	Reverse Recovery Time Reverse Recovery Charge	T _J = 25°C		225	260	no
rr		T _J = 125°C		400	480	ns
Q _{rr}		$I_{SD} = 21A^{\textcircled{3}}$ $T_{J} = 25^{\circ}C$		1.00		
G _{rr}		$di_{SD}/dt = 100A/\mu s$ $T_{J} = 125^{\circ}C$		2.50		μC
1	Reverse Recovery Current	$V_{DD} = 100V$ $T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$		9.1		A
'rrm				12.9		A
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 21A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 333V$, $T_J = 125^{\circ}C$			20	V/ns

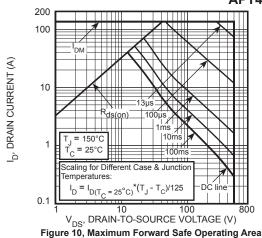
- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25$ °C, L = 4.22mH, $R_G = 25\Omega$, $I_{AS} = 21A$.
- (3) Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}.
 C_{o(er)} is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}. To calculate C_{o(er)} for any value of V_{DS} less than V_{(BR)DSS}, use this equation: C_{o(er)} = -1.84E-7/V_{DS}^2 + 3.75E-8/V_{DS} + 1.05E-10.
- \bigcirc R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

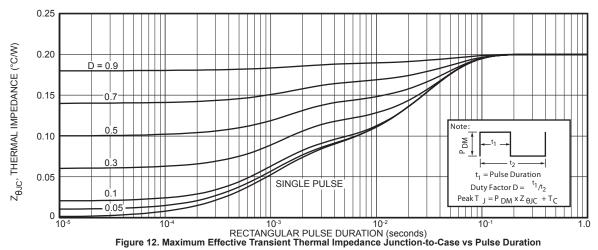
Microsemi reserves the right to change, without notice, the specifications and information contained herein.



50-8084 Rev F 8-2011

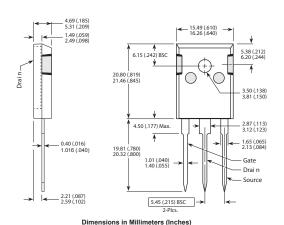


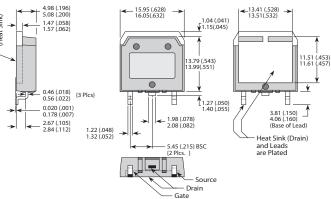




TO-247 (B) Package Outline

@1 SAC: Tin, Silver, Copper





D³PAK Package Outline

@3 100% Sn Plated

Dimensions in Millimeters (Inches)